

Case Details

Wednesday, June 25, 2008

10:57:30 AM

Filtered to show: (ID)-238

Case 238: University of Dayton

Company	University of Dayton	Opened By	Barbara Cabico
Customer	Andrew Saragangan	Assigned To	Ehrin Poklen
Product	XP-1	Serial Number	558
Opened Date	11-Jun-08	Priority	Normal
Due Date		Status	Resolved
Resolved Date	17-Jun-08	Repair Location	Repair at Ambios
Warranty Repair	No	Knowledge Base	
System Inventory		Attachments	0(0)

Problem Description

It looks like that noise is related to the force settings which may have been affected by a partial crash of the sensor. It is impossible to tell without the instrument here. There also may be a static charge on your sample which may be affecting the USB communication as well.

We have seen older instruments lose communication when any kind of ESD is introduced to the system, so the two in conjunction may be increasing this phenomena.

Instrument Diagnosis

Instrument would not engage, but sensor looked fine. USB circuit intermittent due to older USB jack. Rack Wire disengaged

Repairs Made:

Realigned sensor, new 3rd order fit, installed new rack wire, replaced the laser, multiple scans, baselines. Also, reconnectorized all the quick releases.

Comments

Final Tests Performed

Parts Replaced

Rack Wire
Laser
USB Jack
PCB